SERIAL NO. ATTY, DOCKET NO. **FORM PTO-1449** 10/749,688 I-2-0562.1US U.S. DEPARTMENT OF COMMERCE **APPLICANT** PATENT AND TRADEMARK OFFICE John David Kaewell, Jr. INFORMATION DISCLOSURE **GROUP** FILING DATE STATEMENT BY APPLICANT 2816 December 31, 2003 (Use several sheets if necessary) U.S. PATENT DOCUMENTS FILING DATE IF APPROPRIATE SUBCLASS CLASS EXAMINER DOCUMENT NUMBER BUTTIAL Farnworth 04/1991 5,012,323 AA Mo Farnworth et al. 01/1997 5,593,927 AB Farnworth et al. 01/2001 6,169,329 AC King et al. 03/2001 6,207,474 AD Forbes et al. 04/2002 6,376,909 ΑE Cobbley et al. 01/2004 6,682,955 AF Koopmans 03/2004 6,706,557 AG FOREIGN PATENT DOCUMENTS TRANSLATION NO CLASS COUNT DOCUMENT NUMBER DATE OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Gahagan et al., "RF (Gigahertz) ATE Production Testing On-Wafer: Options and Tradeoffs," IEEE, 1999 International Test Conference. ΑH Stoukatch et al., "High Density 3-D Stack Structure for Sip Solutions," IMEC, Kapeldreef 75, 3001 Leuven, Belguim, Internet: http://www.imec.be. ΑI Simon et al., "Interconnects and Transitions in Multilayer LTCC Multichip Modules for 24 GHz ISM-Band Applications," IEEE International Microwave Symposium (IMS-2000), June 2000, pgs. 1047-1050. AJ.

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